

# Cascade Velox™

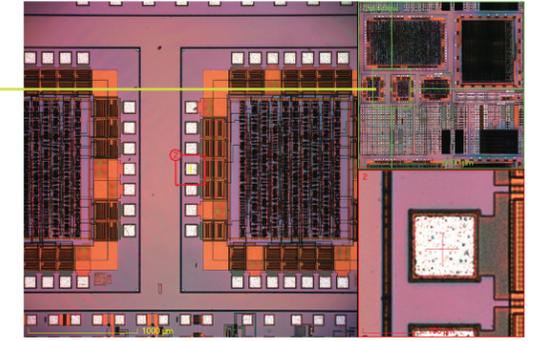
Probe Station Control Software

## Customizable quick launch bar

- Quick access to most important applications, such as WaferMap, ControlCenter, Spectrum™ Vision System and WinCal XE™

## CellView

- Stitched image of the full IC for fastest on-screen navigation within the die



## Start menu

- Windows-like quick-action start menu, making it easy to find functions and settings
- Lists most-used programs for quick start up

## Scope follow mode

- Synchronizes the movement of the chuck and the microscope Z-axis

## Vision

- Pattern recognition for automated wafer and die alignment
- Automation for index measurement, focusing and auxiliary site alignment

## Image analysis

- Measuring function accurately measures the pad size, pad pitch and die size
- Snapshot function makes it easy to use images for documentation purposes

## Control center

- Easy access to all navigation and control elements
- Docking function enables seamless integration into the windows desktop

## Wizard-style dialog boxes

- Guided procedures for index setting, wafer and probe card theta alignments

## Multi-view layout

- Select the layout of up to eight detailed zoom windows

## Software joystick

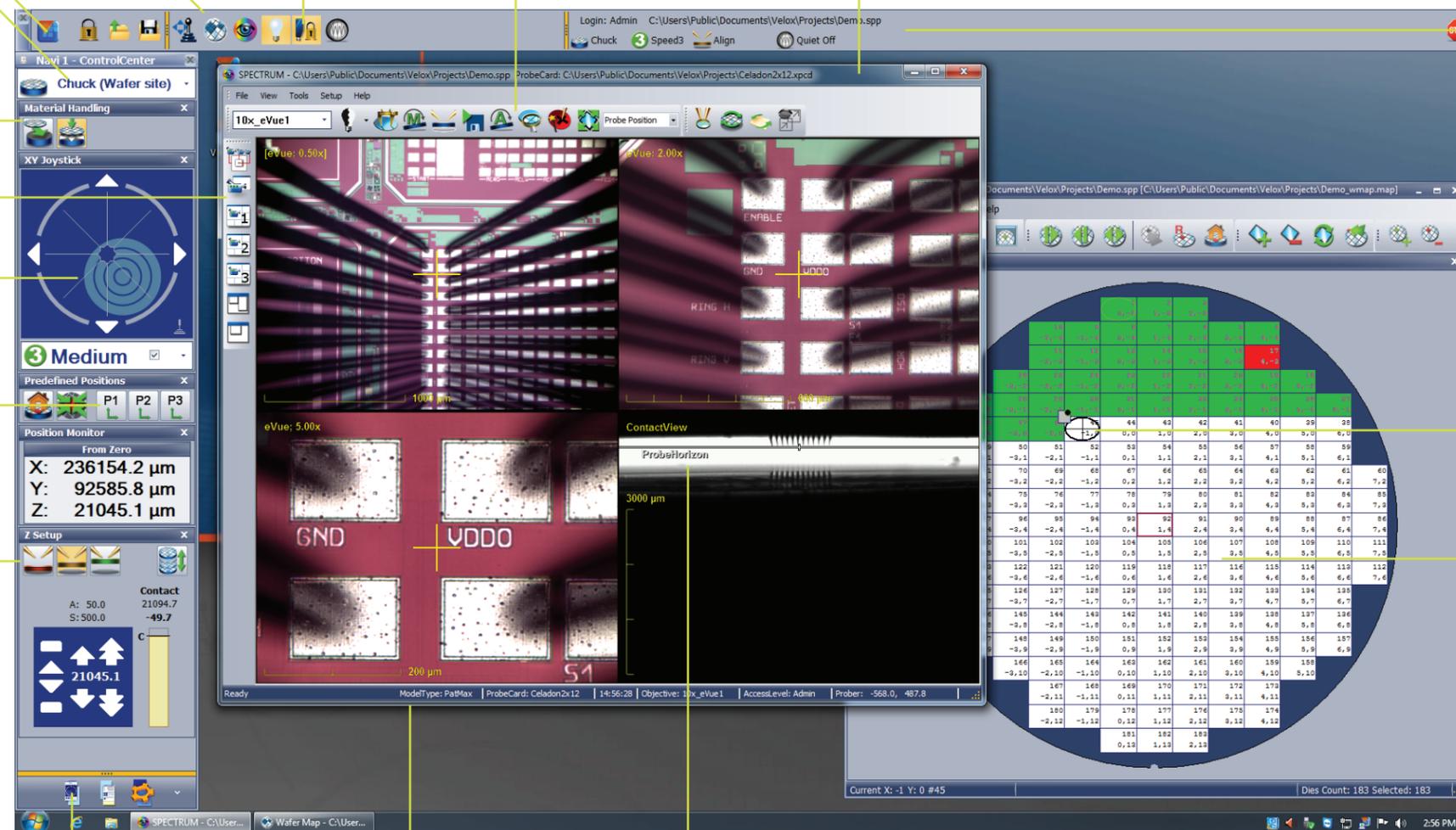
- Intuitive navigation with digital or analogue operation
- Graphical position feedback, indicating exact location of current die on the wafer

## Programmable position buttons

- Memorize user-defined positions referenced to either the user reference or zero position

## Z control

- Easy access to three programmed Z and chuck lift functions to place chuck at a safe height



## Status bar

- System status notifications confirm the measurement setup is correct and ready

## Position tracking

- Perfect for in-die navigation
- Easy to view the current position on the wafer

## WaferMap

- Fully-customizable from single die to sub-die mapping, binning and other useful features
- Save maps in plain text format

## WaferMap features

- Integrated Z-profiling for accurate contact quality
- Multiple wafer view, fully enlarged
- Clustering for parallel testing >2,000,000 die

## First navigation tab

- Safe operation of the system by using programmed functions
- Pre-programmed positions prevent errors caused by accidental clicks

## Multi-camera imaging

- Up to four simultaneous live views for accurate probe tip placement

## ProbeHorizon™

Three-click wizard for:

- Fast and easy wafer loading
- Set contact quickly and safely
- Easy probe tip adjustment and planarization
- Minimizes probe and/or wafer damage